

#### "The bitterness of poor quality remains long after the sweetness of low price is forgotten."

- Benjamin Franklin -

Santa Clara, CA August 2019

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#### The key to **Designing Reliable Storage Systems Axel Mehnert VP Marketing & Strategy** EMBD-101-A-1: Embedded Applications, Part 1 - Drive Design



## System Level Reliability

- Some quality needs to be by-design
- Our design and reliability target: Highest correction performance with guaranteed error floor

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• UBER at no less than 1x10<sup>-16</sup> worst case





#### Lifetime RBER



Cross-temp program at -40°C read at different temperatures

After calibration, RBER between 2x10<sup>-4</sup> and 2x10<sup>-3</sup> (EOL & worst case)



#### **Typical ECC performance** plots



"LDPC Code Concepts and Performance on High-Density Flash Memory", Erich F. Haratsch, Flash Memory Summit 2014

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# Where exactly is the error floor of the ECC you are using?



"LDPC Code Concepts and Performance on High-Density Flash Memory", Erich F. Haratsch, Flash Memory Summit 2014





RBER





RBER







#### RAID vs. TempRAID

#### RAID (permanent)

Block A	Block B	Block C	Block D
User data	User data	User data	Parity

#### TempRAID



Keep pSLC blocks with RAID as backup until TLC block is successfully written

- WAF increase
- Performance impact
- RAID is not always the solution





#### RAID vs. TempRAID

Protection Mechanism	Capacity Impact	Recovery Time	Protection Strength
Read-Verify (temporary SLC RAID)	None	Small	High (if low error-floor ECC is used)





#### Summary

- Pushing ECC performance to higher RBER may introduce a higher error floor
- RAID as countermeasure to higher UBER is costly (WAF, capacity, performance)
- Low-Error-Floor ECC (e.g. GCC)
  - Allows cheaper and reliable countermeasure (Read-Verify)

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Allows different/less-overhead RAID structures





#### Final Thoughts...

Your key take away for the summit

- Watch for the error floor
- Is UBER plotted down to 10<sup>-16</sup> and beyond?
- Don't trust dotted lines those may be based on assumptions





## "Small things make perfection, but perfection is no small thing"

- Henry Royce -

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# The secret to Designing Reliable Storage Systems

**Additional Information** 





## System Level Reliability Tests

Flash Memory Summit

- Subsequent full drive writes (cycles) / drive reads (drive reads plotted in [s])
- Read errors are tracked, first one is highlighted
- Test stops at first failed write command
- 10x difference in lifetime of different SSDs!

315 640 310 630 time [s] [s] 305 300 610 295 600 2000 4000 6000 8000 10000 12000 0 cycle seq. READ whole device 1800 first read error 700 1600 600 1400 500 increase from [S] time [s] 1200 ime read-retrv 400 1000 300 800 200 600 100 400 200 400 600 1200 1400 800 1000 0 cycle

seq. READ whole device



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## Calibration can be carried out by firmware in configurable intervals during operation



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#### **Error Correction**



Santa Clara, CA August 2019 Source: "An Efficient Algorithm for Finding Dominant Trapping Sets of LDPC Codes" Mehdi Karimi, Student Member, IEEE and Amir H. Banihashemi, Senior Member, IEEE

- LDPC codes are not simulated down to JEDEC specified rates (=  $10^{-16}$ for enterprise), but only down to ~ $10^{-10}$
- For the further trend methods like "importance sampling" are used where a small subset of the codewords is used for estimation
  - This educated guess is an orientation but nothing that can be relied on!

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#### **Error Correction**







(6,32)-regular LDPC code with construction field  $GF(2^8)$ , and the (4032,3307) RS-based Gallager (60,63)-regular quasi-cyclic LDPC code with construction field  $GF(2^6)$ .

"A Class of Low-Density Parity-Check Codes Constructed Based on Reed-Solomon Codes With Two Information Symbols", Ivana Djurdjevic, Jun Xu, Khaled Abdel-Ghaffar, *Member, IEEE*, and Shu Lin, *Fellow*, *IEEE*, IEEE COMMUNICATIONS LETTERS, VOL. 7, NO. 7, JULY 2003





#### **Error Correction**

- LDPC
  - High performance
  - Error-floor unknown estimation only (e.g. importance sampling)
  - Full simulation not feasible
  - Many different "quality" grades depending on implementation and alignment to specific Flash technology and channel model
- Generalized Concatenated Code (GCC)
  - High correction performance
  - Error-floor: analytical determination possible
  - Low-Error Floor
  - Guaranteed correction capability





- Two definitions
  - Scientific: Uncorrectable Bit Error Rate a statistic measure of the probability of one erroneous bit after processing in the the ECC unit (module level).
  - JEDEC:  $UBER = \frac{number of data \, errors \, (sectors)}{number of bits read}$  during the TBW rating limit of the drive (sector errors of the whole system).
  - Large difference between the two depending on the ECC frame size and system sector size





#### **Reliability Enhancement Techniques**

Technique	Impact on Average Read Performance	Impact on Trail Performance (Read)	WAF	Management Overhead
ECC (hard-decision)				None
ECC (soft-decision)				Negligible
Read Retry				Voltage levels
Flash Calibration				None
RAID (3:1)				Medium
RAID (127:1)				Low
Temporary RAID (e.g. Read-Verify)				Medium
<b>Dynamic Data-Refresh</b> Santa Clara,				Low
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#### **E2E Data-Path Protection**



- Protection against radiation (single event effects)
- Detection & correction of errors in the main memory
- Comprehensive protection of the complete datapath

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#### **RBER – Lifetime Monitoring**

http://www.hySMART					
File Device ATA Identify Device ATA SMART Hyperstone Vendor Data Log					
Device: 01 - HYPER FLASHDISK   \$ Disconnec	t Refresh Data Save All Data				
Device List Device Status ATA Id. Dev. Target Info Life Time Info FW Version SMART Data SMART Attr. Thr. Remap Wear Level Log					
- Spare Block Information					
Number Remaining Spare Blocks (All Chips): 89 [of 89]	)				
Percentage Remaining Spare Blocks (All Chips): 100 0	100				
Number Remaining Spare Blocks (Worst Chip): 89 [of 89]					
Percentage Remaining Spare Blocks (Worst Chip): 100 0	100				
Erase Block Information - Remaining Card Life Percentage Remaining Card Life: 100 10 100 100 100 100 100 100 100 100					
ECC Error Information - Number of ECC Errors					
Total w/o Startup: 8030141 Correctable: 8030141 Uncorrectable: 0					
Total Startup: 119714 Correctable: 119714 Uncorrectable: 0					
ECC Error Histogram - 40 bit ECC					
0 0 0 0 0 0 0 0 0 0 0 0 0 0					
Device: connected - State: OK - SMART: support	orted enabled Threshold: not exceeded				

With the Hyperstone **hySMART** tool you can monitor the corrected bit errors during lifetime to be confident your system works within operating conditions and to predict lifetime for your specific use-case and mission profile.



## hyReliability FlashXE®



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